

MCP-S330

**Precise measurement of surface resistivity [ $\Omega/\text{sq.}$ ] and volume resistivity [ $\Omega\cdot\text{cm}$ ] without affection by the sample shape**

## *Low Resistivity Mapping System*

Variations of thickness and composition in conductive films, metals, Metallic thin films, etc. are clear at a glance.

Capable of mapping samples up to 300 mm sq. and continuous measurement of multiple sheets of sample



*LorestaGX*  
*Low resistivity meter*

***Nittoseiko Analytech Co., Ltd.***

# Low Resistivity Mapping System (MCP-S330)

- Accurate measurement of surface resistivity [ $\Omega/\text{sq.}$ ] and volume resistivity [ $\Omega\cdot\text{cm}$ ]

Accurate and easy measurement of material resistivity

## 4-Pin Probe Method

High-precision measurement that eliminates contact resistance and lead resistance between sample and probe  
Dedicated probe of Spring Contact method that keeps pressing pressure, pin to pin distance, and contact area constant.

### Uses

- Production engineering
- Quality control
- R & D

### Applications

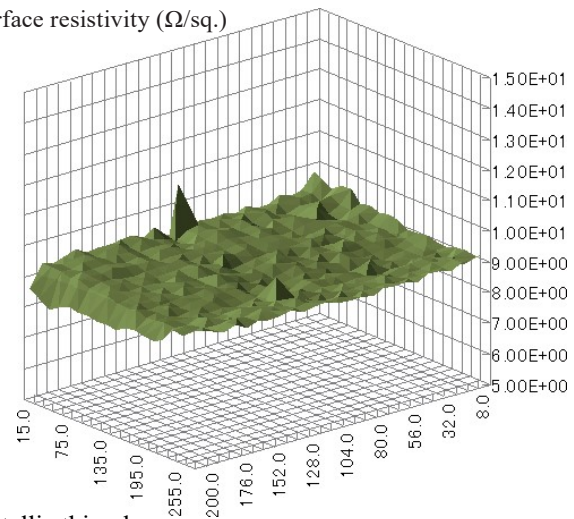
- Metals, Metallic thin films, conductive coatings, conductive films, sheets, etc.

### Features

- Measurable from  $10^{-4}$  to  $10^7 \Omega$  range in connection with Loresta GX
- Full automation: Measurement, Arithmetic, Data processing, and 3D graph output
- Sample sizes up to 300mm sq. and multiple sheets of sample is also measurable
- Coordinate data can also be imported from an external source besides three types of measurement position sets: grid input, line input, and sequential input
- Comparator function that marks the measurement point on the screen where the measurement result is out of the specified range

Standard Specification for Low Resistivity Mapping System	
Effective measurement range	X-axis: 300 mm Y-axis: 300 mm Z-axis: 50mm
Sample thickness	40mm or lower
Probe vertical operation height	Approx. 50mm
Positioning resolution	X-axis, Y-axis, Z-axis: 0.1mm
Repetitive Positioning precision	X-axis, Y-axis : $\pm 0.08\text{mm}$ Z-Axis $\pm 0.1 \text{mm}$
Probe for mapping	Series 4-pin probe Pin-to-pin 1.0mm, 1.5mm, (5mm pitch)
Sample measurement pedestal	White PVC sheet or glass plate X and Y axes with 50mm pitch scale sheet
Sample delivery	Hand-placed (Not compatible with automatic carrier machines, etc.)
Interface	USB port
Electric power Source	85 to 264 VAC(50/60Hz) Power consumption: 64VA
External dimensions and weight	Approx. 543W×492D×410H (mm), Approx. 22kg

Metallic thin film  
Surface resistivity ( $\Omega/\text{sq.}$ )



Metallic thin glass  
Surface resistivity ( $\Omega/\text{sq.}$ )

